# **1-Bit 20 Mb/s Dual-Supply Level Translator**

The NLSX4401 is a 1-bit configurable dual-supply bidirectional auto sensing translator that does not require a directional control pin. The I/O V<sub>CC</sub> and I/O V<sub>L</sub> ports are designed to track two different power supply rails, V<sub>CC</sub> and V<sub>L</sub> respectively. Both the V<sub>CC</sub> and V<sub>L</sub> supply rails are configurable from 1.5 V to 5.5 V. This allows voltage logic signals on the V<sub>L</sub> signals on the V<sub>CC</sub> side, and vice-versa.

The NLSX4401 translator has integrated 10 k $\Omega$  pull–up resistors on the I/O lines. The integrated pull–up resistors are used to pull up the I/O lines to either V<sub>L</sub> or V<sub>CC</sub>. The NLSX4401 is an excellent match for open–drain applications such as the I<sup>2</sup>C communication bus.

#### Features

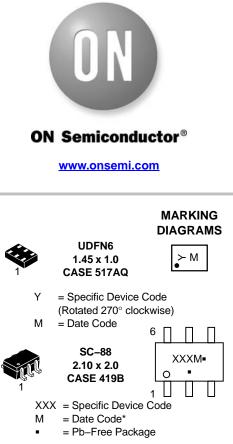
- $V_L$  can be Less than, Greater than or Equal to  $V_{CC}$
- Wide V<sub>CC</sub> Operating Range: 1.5 V to 5.5 V Wide V<sub>L</sub> Operating Range: 1.5 V to 5.5 V
- High Speed with 24 Mb/s Guaranteed Date Rate
- Low Bit-to-Bit Skew
- Enable Input and I/O Pins are Overvoltage Tolerant (OVT) to 5.5 V
- Non-preferential Powerup Sequencing
- Power–Off Protection
- Integrated 10 kΩ Pull–up Resistors
- Small Space Saving Packages: 1.45 mm x 1.0 mm UDFN6 Package SC-88/SC70-6/SOT-363 Package
- These Devices are Pb-Free and are RoHS Compliant

#### **Typical Applications**

- I<sup>2</sup>C, SMBus, PMBus
- Low Voltage ASIC Level Translation
- Mobile Phones, PDAs, Cameras

#### Important Information

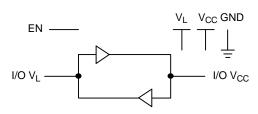
- ESD Protection for All Pins
  - Human Body Model (HBM) > 5000 V



(Note: Microdot may be in either location)

\*Date Code orientation and/or position may vary depending upon manufacturing location.

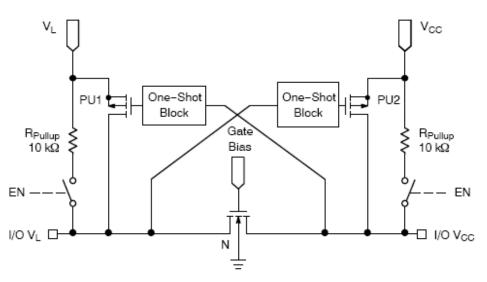




#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NLSX4401MU1TCG	UDFN6 (Pb–Free)	3000 / Tape & Reel
NLSX4401DFT2G (In Development)	SC–88/ SC70–6/ SOT–363 (Pb–Free)	3000 / Tape & Reel

<sup>+</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.





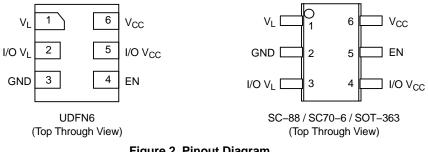


Figure 2. Pinout Diagram

#### **PIN ASSIGNMENT**

Pins	Description
V <sub>CC</sub>	V <sub>CC</sub> Supply Voltage
VL	V <sub>L</sub> Supply Voltage
GND	Ground
EN	Output Enable, Referenced to $V_L$
I/O V <sub>CC</sub>	I/O Port, Referenced to V <sub>CC</sub>
I/O V <sub>L</sub>	I/O Port, Referenced to VL

**FUNCTION TABLE** 

EN	Operating Mode
L	Hi–Z
н	I/O Buses Connected

### MAXIMUM RATINGS

Symbol	Parameter	Value	Condition	Unit
V <sub>CC</sub>	High-side DC Supply Voltage	-0.5 to +7.0		V
VL	High-side DC Supply Voltage	-0.5 to +7.0		V
$I/O V_{CC}$	V <sub>CC</sub> –Referenced DC Input/Output Voltage	-0.5 to +7.0		V
I/O V <sub>L</sub>	V <sub>L</sub> -Referenced DC Input/Output Voltage	-0.5 to +7.0		V
V <sub>EN</sub>	Enable Control Pin DC Input Voltage	-0.5 to +7.0		V
I <sub>I/O_SC</sub>	Short–Circuit Duration (I/O $V_L$ and I/O $V_{CC}$ to GND)	±50	Continuous	mA
I <sub>I/OK</sub>	Input/Output Clamping Current (I/O $\rm V_L$ and I/O $\rm V_{CC})$	-50	V <sub>I/O</sub> < 0	mA
T <sub>STG</sub>	Storage Temperature	-65 to +150		°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### **RECOMMENDED OPERATING CONDITIONS**

Symbol	Parameter	Min	Max	Unit
V <sub>CC</sub>	High-side Positive DC Supply Voltage	1.5	5.5	V
VL	High-side Positive DC Supply Voltage	1.5	5.5	V
V <sub>EN</sub>	Enable Control Pin Voltage	GND	5.5	V
V <sub>IO_VCC</sub>	I/O Pin Voltage (Side referred to $V_{CC}$ )	GND	5.5	V
V <sub>IO_VL</sub>	I/O Pin Voltage (Side referred to $V_L$ )	GND	5.5	V
Δt/ΔV	Input Transition Rise and Fall Rate A– or B–Ports, Push–Pull Driving Control Input		10 10	ns/V
T <sub>A</sub>	Operating Temperature Range	-55	+125	°C

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

		Test Conditions (Note 2)	–55°C to +125°C			
Symbol	Parameter		Min	Тур	Max	Unit
V <sub>IHC</sub>	I/O V <sub>CC</sub> Input HIGH Voltage		$V_{CC} - 0.4$	_	-	V
V <sub>ILC</sub>	I/O V <sub>CC</sub> Input LOW Voltage		-	_	0.15	V
VIHL	I/O VL Input HIGH Voltage		$V_{L} - 0.4$	_	-	V
V <sub>ILL</sub>	I/O VL Input LOW Voltage		-	_	0.15	V
V <sub>IH</sub>	Control Pin Input HIGH Voltage		0.65 * V <sub>L</sub>	_	-	V
VIL	Control Pin Input LOW Voltage		-	_	0.35 * V <sub>L</sub>	V
V <sub>OHC</sub>	I/O Vcc Output HIGH Voltage	I/O V <sub>CC</sub> source current = 20 $\mu$ A	2/3 * V <sub>CC</sub>	_	-	V
V <sub>OLC</sub>	I/O Vcc Output LOW Voltage	I/O V <sub>CC</sub> sink current = 1 mA	-	_	0.4	V
VOHL	I/O V∟Output HIGH Voltage	I/O V <sub>L</sub> source current = 20 $\mu$ A	2/3 * V <sub>L</sub>	_	_	V
V <sub>OLL</sub>	I/O V₋Output LOW Voltage	I/O V <sub>L</sub> sink current = 1 mA	-	_	0.4	V
IQVCC	V <sub>CC</sub> Supply Current Supply Current	I/O V <sub>CC</sub> and I/O V <sub>L</sub> unconnected, V <sub>EN</sub> = V <sub>L</sub> V <sub>L</sub> = 5.5 V, V <sub>CC</sub> = 0 V V <sub>L</sub> = 0 V, V <sub>CC</sub> = 5.5 V	- - -	0.5 _ _	2.0 1.0 -1.0	μΑ
I <sub>QVL</sub>	V₋Supply Current Supply Current	I/O V <sub>CC</sub> and I/O V <sub>L</sub> unconnected, V <sub>EN</sub> = V <sub>L</sub> V <sub>L</sub> = 5.5 V, V <sub>CC</sub> = 0 V V <sub>L</sub> = 0 V, V <sub>CC</sub> = 5.5 V	- - -	0.3 _ _	1.5 -1.0 1.0	μΑ
I <sub>TS-VCC</sub>	V <sub>CC</sub> Tristate Output Mode	I/O V <sub>CC</sub> and I/O V <sub>L</sub> unconnected, V <sub>EN</sub> = GND	-	0.1	1.0	μΑ
$I_{\text{TS-VL}}$	V <sub>L</sub> Tristate Output Mode Supply Cur- rent	I/O V <sub>CC</sub> and I/O V <sub>L</sub> unconnected, V <sub>EN</sub> = GND	-	0.1	1.0	μΑ
Ι	Enable Pin Input Leakage Current		-	_	1.0	μΑ
I <sub>OFF</sub>	I/O Power-Off Leakage Current	I/O V <sub>CC</sub> Port, V <sub>CC</sub> = 0 V, V <sub>L</sub> = 0 to 5.5 V	-	_	1.0	μΑ
		I/O VL Port, VCC = 0 to 5.5 V, $V_L = 0$ V	_	_	1.0	
I <sub>OZ</sub>	I/O Tristate Output Mode Leakage Current		-	0.1	1.0	μΑ
R <sub>PU</sub>	Pull–Up Resistors I/O V <sub>L</sub> and V <sub>C</sub>		-	10	-	kΩ

DC ELECTRICAL CHARACTERISTICS (VL	= 1.5 V to 5.5 V and $V_{CC}$ = 1.5 V to 5.5	V, unless otherwise specified) (Note 1)
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Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 1. Typical values are for  $V_L = +1.8 \text{ V}$ ,  $V_{CC} = +3.3 \text{ V}$  and  $T_A = +25^{\circ}\text{C}$ . 2. All units are production tested at  $T_A = +25^{\circ}\text{C}$ . Limits over the operating temperature range are guaranteed by design.

#### TIMING CHARACTERISTICS - RAIL-TO-RAIL DRIVING CONFIGURATIONS

(I/O test circuit of Figures 3 and 4,  $C_{LOAD}$  = 15 pF, driver output impedance  $\leq$  50  $\Omega$ ,  $R_{LOAD}$  = 1 M $\Omega$ )

			<b>-40°C to +85°C</b> (Notes 3 & 4)			
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V <sub>L</sub> = 1.5 V, V	V <sub>CC</sub> = 1.5 V	1	1	•		
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Rise Time			9	32	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Fall Time			11	20	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Rise Time			20	30	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Fall Time			10	13	ns
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O $V_L$ , $V_L$ to $V_{CC}$ )			7	16	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O $V_{CC}$ , $V_{CC}$ to $V_L$ )			12	15	ns
t <sub>EN</sub>	Enable Time				50	ns
t <sub>DIS</sub>	Disable Time				300	ns
<b>t</b> PPSKEW	Part-to-Part Skew				2	ns
MDR	Maximum Data Rate		15			Mbps
V <sub>L</sub> = 1.5 V, V	/ <sub>CC</sub> = 5.5 V	·			•	
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Rise Time			9	12	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Fall Time			17	30	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Rise Time			2	4	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Fall Time			3	7	ns
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O $V_L$ , $V_L$ to $V_{CC}$ )			14	24	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O $V_{CC}$ , $V_{CC}$ to $V_L$ )			3	5	ns
t <sub>EN</sub>	Enable Time				40	ns
t <sub>DIS</sub>	Disable Time				250	ns
<b>t</b> PPSKEW	Part-to-Part Skew				2	ns
MDR	Maximum Data Rate		20			Mbps
V <sub>L</sub> = 1.8 V, V	$V_{\rm CC} = 2.8 \text{ V}$			•		
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Rise Time			11	18	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Fall Time			10	15	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Rise Time			12	15	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Fall Time			5	8	ns
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O $V_L$ , $V_L$ to $V_{CC}$ )			7	10	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O $V_{CC}$ , $V_{CC}$ to $V_L$ )			5	9	ns
t <sub>EN</sub>	Enable Time				50	ns
t <sub>DIS</sub>	Disable Time				300	ns
<b>t</b> PPSKEW	Part-to-Part Skew				2	ns
MDR	Maximum Data Rate		20			Mbps

I/O V<sub>CC</sub> Rise Time t<sub>RVCC</sub> 8 12 ns Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product perfor-

mance may not be indicated by the Electrical Characteristics if operated under different conditions.

3. Typical values are for the specified  $V_L$  and  $V_{CC}$  at  $T_A = +25^{\circ}C$ . All units are production tested at  $T_A = +25^{\circ}C$ . 4. Limits over the operating temperature range are guaranteed by design.

5. Skew is the variation of propagation delay between output signals and applies only to output signals on the same port (I/O\_VLn or I/O\_VCCn) and switching with the same polarity (LOW-to-HIGH or HIGH-to-LOW). Skew is defined by applying a single input to the two input channels and measuring the difference in propagation delays between the output channels.

#### TIMING CHARACTERISTICS - RAIL-TO-RAIL DRIVING CONFIGURATIONS (continued)

(I/O test circuit of Figures 3 and 4,  $C_{LOAD}$  = 15 pF, driver output impedance  $\leq$  50  $\Omega$ ,  $R_{LOAD}$  = 1 M $\Omega$ )

				10°C to +8 Notes 3 &		Unit
Symbol	Parameter Te	Test Conditions	Min	Тур	Max	
/ <sub>L</sub> = 2.5 V, V	$V_{\rm CC} = 3.6 \text{ V}$					
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Fall Time			8	12	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Rise Time			7	10	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Fall Time			5	7	ns
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O $V_L$ , $V_L$ to $V_{CC}$ )			7	10	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O $V_{CC}$ , $V_{CC}$ to $V_L$ )			5	8	ns
t <sub>EN</sub>	Enable Time				40	ns
t <sub>DIS</sub>	Disable Time				225	ns
t <sub>PPSKEW</sub>	Part-to-Part Skew				2	ns
MDR	Maximum Data Rate		24			Mbps
V <sub>L</sub> = 2.8 V, V	/ <sub>CC</sub> = 1.8 V				1	
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Rise Time			13	20	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Fall Time			7	10	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Rise Time			8	13	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Fall Time			9	15	ns
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O $V_L$ , $V_L$ to $V_{CC}$ )			6	9	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O $V_{CC}$ , $V_{CC}$ to $V_L$ )			7	12	ns
t <sub>EN</sub>	Enable Time				60	ns
t <sub>DIS</sub>	Disable Time				250	ns
<b>t</b> PPSKEW	Part-to-Part Skew				2	ns
MDR	Maximum Data Rate		24			Mbps
V <sub>L</sub> = 3.6 V, V	/ <sub>CC</sub> = 2.5 V		•	•	1	1
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Rise Time			9	12	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Fall Time			6	9	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Rise Time			6	12	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Fall Time			7	12	ns
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O $V_L$ , $V_L$ to $V_{CC}$ )			5	7	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O $V_{CC}$ , $V_{CC}$ to $V_L$ )			6	9	ns
t <sub>EN</sub>	Enable Time				50	ns
t <sub>DIS</sub>	Disable Time		1	1	250	ns
<b>t</b> PPSKEW	Part-to-Part Skew		1	1	2	ns
MDR	Maximum Data Rate		24	1	1	Mbps
/ <sub>L</sub> = 5.5 V, V	/ <sub>CC</sub> = 1.5 V	ł			1	
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Rise Time			13	20	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Fall Time			6	9	ns

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

3. Typical values are for the specified V<sub>L</sub> and V<sub>CC</sub> at  $T_A = +25^{\circ}C$ . All units are production tested at  $T_A = +25^{\circ}C$ . 4. Limits over the operating temperature range are guaranteed by design.

5. Skew is the variation of propagation delay between output signals and applies only to output signals on the same port (I/O\_VLn or I/O\_VCCn) and switching with the same polarity (LOW-to-HIGH or HIGH-to-LOW). Skew is defined by applying a single input to the two input channels and measuring the difference in propagation delays between the output channels.

#### TIMING CHARACTERISTICS - RAIL-TO-RAIL DRIVING CONFIGURATIONS (continued)

(I/O test circuit of Figures 3 and 4,  $C_{LOAD}$  = 15 pF, driver output impedance  $\leq$  50  $\Omega$ ,  $R_{LOAD}$  = 1 M $\Omega$ )

Symbol	Parameter		-40°C to +85°C (Notes 3 & 4)			
		Test Conditions	Min	Тур	Max	Unit
V <sub>L</sub> = 5.5 V, V	V <sub>CC</sub> = 1.5 V	·				
t <sub>RVL</sub>	I/O V <sub>L</sub> Rise Time			8	10	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Fall Time			20	27	ns
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O $V_L$ , $V_L$ to $V_{CC}$ )			5	8	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O $V_{CC}$ , $V_{CC}$ to $V_L$ )			14	24	ns
t <sub>EN</sub>	Enable Time					ns
t <sub>DIS</sub>	Disable Time					ns
t <sub>PPSKEW</sub>	Part-to-Part Skew				2	ns
MDR	Maximum Data Rate		20			Mbps
V <sub>L</sub> = 5.5 V, V	/ <sub>CC</sub> = 5.5 V					
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Rise Time			5	7	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Fall Time			6	8	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Rise Time			5	7	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Fall Time			4	7	ns
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O $V_L$ , $V_L$ to $V_{CC}$ )			4	6	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O $V_{CC}$ , $V_{CC}$ to $V_L$ )			4	6	ns
t <sub>EN</sub>	Enable Time				30	ns
t <sub>DIS</sub>	Disable Time				225	ns
<b>t</b> PPSKEW	Part-to-Part Skew				2	ns
MDR	Maximum Data Rate		24	1		Mbps

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

3. Typical values are for the specified V<sub>L</sub> and V<sub>CC</sub> at T<sub>A</sub> = +25°C. All units are production tested at T<sub>A</sub> = +25°C.

4. Limits over the operating temperature range are guaranteed by design.

5. Skew is the variation of propagation delay between output signals and applies only to output signals on the same port (I/O\_VLn or I/O\_VCCn) and switching with the same polarity (LOW-to-HIGH or HIGH-to-LOW). Skew is defined by applying a single input to the two input channels and measuring the difference in propagation delays between the output channels.

#### TIMING CHARACTERISTICS - OPEN DRAIN DRIVING CONFIGURATIONS

(I/O test circuit of Figures 5 and 6, C<sub>LOAD</sub> = 15 pF, driver output impedance  $\leq$  50  $\Omega$ , R<sub>LOAD</sub> = 1 M $\Omega$ )

				<b>40°C to +85°C</b> (Notes 6 & 7)			
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit	
$V_{L} = 1.5 V, V_{CC} = 1.5 V$							
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Rise Time			55	70	ns	
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Fall Time			7	14	ns	
t <sub>RVL</sub>	I/O V <sub>L</sub> Rise Time			50	65	ns	
t <sub>FVL</sub>	I/O $V_L$ Fall Time			7	12	ns	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

6. Typical values are for the specified V<sub>L</sub> and V<sub>CC</sub> at T<sub>A</sub> = +25°C. All units are production tested at T<sub>A</sub> = +25°C.

7. Limits over the operating temperature range are guaranteed by design.

8. Skew is the variation of propagation delay between output signals and applies only to output signals on the same port (I/O\_VLn or I/O\_VCCn) and switching with the same polarity (LOW-to-HIGH or HIGH-to-LOW). Skew is defined by applying a single input to the two input channels and measuring the difference in propagation delays between the output channels.

#### TIMING CHARACTERISTICS - OPEN DRAIN DRIVING CONFIGURATIONS (continued)

(I/O test circuit of Figures 5 and 6,  $C_{LOAD}$  = 15 pF, driver output impedance  $\leq$  50  $\Omega$ ,  $R_{LOAD}$  = 1 M $\Omega$ )

	Parameter Test Condition		-40°C to +85°C (Notes 6 & 7)			
Symbol		Test Conditions	Min	Тур	Max	Unit
/ <sub>L</sub> = 1.5 V, V	V <sub>CC</sub> = 1.5 V					
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O $V_L$ , $V_L$ to $V_{CC}$ )			20	34	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O $V_{CC}$ , $V_{CC}$ to $V_L$ )			19	34	ns
t <sub>EN</sub>	Enable Time				100	ns
t <sub>DIS</sub>	Disable Time				300	ns
t <sub>PPSKEW</sub>	Part-to-Part Skew				2	ns
MDR	Maximum Data Rate		3			Mbps
V <sub>L</sub> = 1.5 V, V	ν <sub>CC</sub> = 5.5 V					
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Rise Time			22	34	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Fall Time			20	27	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Rise Time			43	55	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Fall Time			6	12	ns
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O $V_L$ , $V_L$ to $V_{CC}$ )			13	26	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O $V_{CC}$ , $V_{CC}$ to $V_L$ )			19	24	ns
t <sub>EN</sub>	Enable Time				80	ns
t <sub>DIS</sub>	Disable Time				250	ns
t <sub>PPSKEW</sub>	Part-to-Part Skew				2	ns
MDR	Maximum Data Rate		3			Mbps
V <sub>L</sub> = 1.8 V, V	/ <sub>CC</sub> = 3.3 V					
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Rise Time			34	40	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Fall Time			1	15	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Rise Time			40	48	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Fall Time			1	2	ns
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O $V_L$ , $V_L$ to $V_{CC}$ )			9	15	ns
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O $V_{CC}$ , $V_{CC}$ to $V_L$ )			6	11	ns
t <sub>EN</sub>	Enable Time				70	ns
t <sub>DIS</sub>	Disable Time				300	ns
<b>t</b> PPSKEW	Part-to-Part Skew				2	ns
MDR	Maximum Data Rate		7			Mbps
V <sub>L</sub> = 5.5 V, V	/ <sub>CC</sub> = 1.5 V		Į	ļ	<u>ļ</u>	1
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Rise Time			44	52	ns
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Fall Time			1	2	ns
t <sub>RVL</sub>	I/O V <sub>L</sub> Rise Time			7	30	ns
t <sub>FVL</sub>	I/O V <sub>L</sub> Fall Time			17	23	ns
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O $V_L$ , $V_L$ to $V_{CC}$ )			10	17	ns

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

6. Typical values are for the specified V<sub>L</sub> and V<sub>CC</sub> at  $T_A = +25^{\circ}C$ . All units are production tested at  $T_A = +25^{\circ}C$ . 7. Limits over the operating temperature range are guaranteed by design.

8. Skew is the variation of propagation delay between output signals and applies only to output signals on the same port (I/O\_VLn or I/O\_VCCn) and switching with the same polarity (LOW-to-HIGH or HIGH-to-LOW). Skew is defined by applying a single input to the two input channels and measuring the difference in propagation delays between the output channels.

#### TIMING CHARACTERISTICS - OPEN DRAIN DRIVING CONFIGURATIONS (continued)

(I/O test circuit of Figures 5 and 6,  $C_{LOAD}$  = 15 pF, driver output impedance  $\leq$  50  $\Omega$ ,  $R_{LOAD}$  = 1 M $\Omega$ )

			<b>-40°C to +85°C</b> (Notes 6 & 7)				
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit	
V <sub>L</sub> = 5.5 V, V	V <sub>CC</sub> = 1.5 V		·				
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O $V_{CC}$ , $V_{CC}$ to $V_L$ )			12	24	ns	
t <sub>EN</sub>	Enable Time				100	ns	
t <sub>DIS</sub>	Disable Time				300	ns	
t <sub>PPSKEW</sub>	Part-to-Part Skew				2	ns	
MDR	Maximum Data Rate		3			Mbps	
V <sub>L</sub> = 5.5 V, V	V <sub>CC</sub> = 5.5 V						
t <sub>RVCC</sub>	I/O V <sub>CC</sub> Rise Time			42	50	ns	
t <sub>FVCC</sub>	I/O V <sub>CC</sub> Fall Time			2	3	ns	
t <sub>RVL</sub>	I/O V <sub>L</sub> Rise Time			44	48	ns	
t <sub>FVL</sub>	I/O V <sub>L</sub> Fall Time			2	3	ns	
t <sub>PDVL-VCC</sub>	Propagation Delay (Driving I/O $V_L$ , $V_L$ to $V_{CC}$ )			4	6	ns	
t <sub>PDVCC-VL</sub>	Propagation Delay (Driving I/O $V_{CC}$ , $V_{CC}$ to $V_L$ )			6	9	ns	
t <sub>EN</sub>	Enable Time				60	ns	
t <sub>DIS</sub>	Disable Time				225	ns	
t <sub>PPSKEW</sub>	Part-to-Part Skew				2	ns	
MDR	Maximum Data Rate		7			Mbps	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

6. Typical values are for the specified V<sub>L</sub> and V<sub>CC</sub> at  $T_A = +25^{\circ}C$ . All units are production tested at  $T_A = +25^{\circ}C$ .

7. Limits over the operating temperature range are guaranteed by design.

Skew is the variation of propagation delay between output signals and applies only to output signals on the same port (I/O\_VLn or I/O\_VCCn) and switching with the same polarity (LOW-to-HIGH or HIGH-to-LOW). Skew is defined by applying a single input to the two input channels and measuring the difference in propagation delays between the output channels.

### **TEST SETUP**

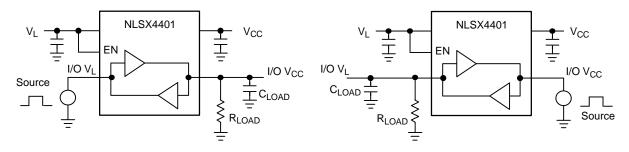




Figure 4. Rail-to-Rail Driving I/O V<sub>CC</sub>

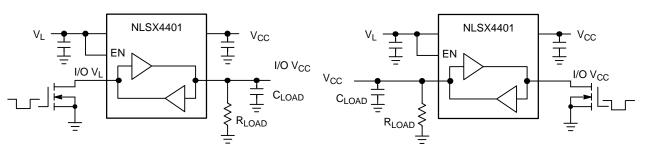


Figure 5. Open–Drain Driving I/O  $V_L$ 

Figure 6. Open–Drain Driving I/O V<sub>CC</sub>

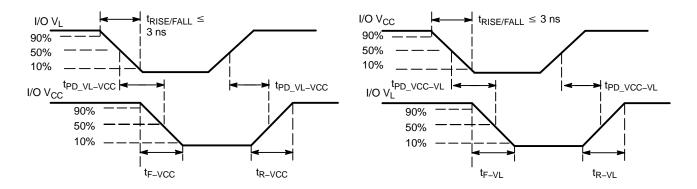
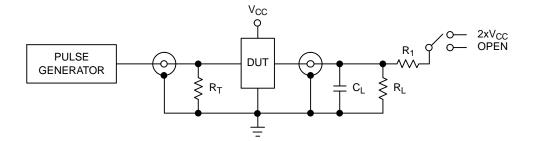
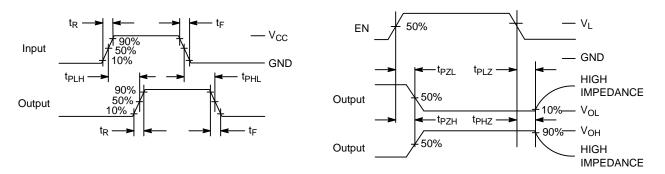


Figure 7. Definition of Timing Specification Parameters



Test	Switch		
t <sub>PZH</sub> , t <sub>PHZ</sub>	Open		
t <sub>PZL</sub> , t <sub>PLZ</sub>	$2 \times V_{CC}$		

 $C_L$  = 15 pF or equivalent (Includes jig and probe capacitance)  $R_L$  =  $R_1$  = 50 k $\Omega$  or equivalent  $R_T$  =  $Z_{OUT}$  of pulse generator (typically 50  $\Omega$ )



#### Figure 8. Test Circuit for Enable/Disable Time Measurement

Figure 9. Timing Definitions for Propagation Delays and Enable/Disable Measurement

#### APPLICATIONS INFORMATION

#### Level Translator Architecture

The NLSX4401 auto sense translator provides bi-directional voltage level shifting to transfer data in multiple supply voltage systems. This device has two supply voltages,  $V_L$  and  $V_{CC}$ , which set the logic levels on the input and output sides of the translator. When used to transfer data from the I/O  $V_L$  to the I/O  $V_{CC}$  ports, input signals referenced to the  $V_L$  supply are translated to output signals with a logic level matched to  $V_{CC}$ . In a similar manner, the I/O  $V_{CC}$  to I/O  $V_L$  translation shifts input signals with a logic level compatible to  $V_{CC}$  to an output signal matched to  $V_L$ .

The NLSX4401 consists of two bi-directional channels that independently determine the direction of the data flow without requiring a directional pin. The one-shot circuits are used to detect the rising or falling input signals. In addition, the one shots decrease the rise and fall time of the output signal for high-to-low and low-to-high transitions.

Each input/output channel has an internal 10 k $\Omega$  pull-up. The magnitude of the pull-up resistors can be reduced by connecting external resistors in parallel to the internal 10 k $\Omega$  resistors.

#### **Input Driver Requirements**

The rise  $(t_R)$  and fall  $(t_F)$  timing parameters of the open drain outputs depend on the magnitude of the pull-up resistors. In addition, the propagation times  $(t_{PHL} / t_{PLH})$ , skew  $(t_{PSKEW})$  and maximum data rate depend on the

impedance of the device that is connected to the translator. The timing parameters listed in the data sheet assume that the output impedance of the drivers connected to the translator is less than 50 k $\Omega$ .

#### Enable Input (EN)

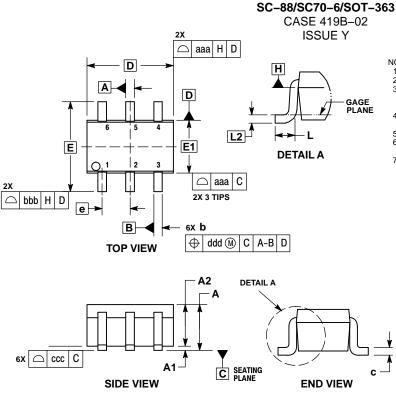
The NLSX4401 has an Enable pin (EN) that provides tri–state operation at the I/O pins. Driving the Enable pin to a low logic level minimizes the power consumption of the device and drives the I/O  $V_{CC}$  and I/O  $V_L$  pins to a high impedance state. Normal translation operation occurs when the EN pin is equal to a logic high signal. The EN pin is referenced to the  $V_L$  supply and has Overvoltage Tolerant (OVT) protection.

#### Power Supply Guidelines

During normal operation, supply voltage  $V_L$  can be greater than, less than or equal to  $V_{CC}$ . The sequencing of the power supplies will not damage the device during the power up operation.

For optimal performance, 0.01  $\mu$ F to 0.1  $\mu$ F decoupling capacitors should be used on the V<sub>CCA</sub> and V<sub>CCB</sub> power supply pins. Ceramic capacitors are a good design choice to filter and bypass any noise signals on the voltage lines to the ground plane of the PCB. The noise immunity will be maximized by placing the capacitors as close as possible to the supply and ground pins, along with minimizing the PCB connection traces.

### PACKAGE DIMENSIONS

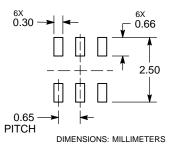


NOTES: 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.

- 2. 3.
- 4.
- 5. 6.
- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. CONTROLLING DIMENSION: MILLIMETERS. DIMENSIONS D AND E1 DO NOT INCLUDE MOLD FLASH, PRO-TRUSIONS, OR GATE BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.20 PER END. DIMENSIONS D AND E1 AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY AND DATUM H. DATUMS A AND B ARE DETERMINED AT DATUM H. DIMENSIONS b AND c APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN 0.08 AND 0.15 FROM THE TIP. DIMENSION b DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08 TOTAL IN EXCESS OF DIMENSION b AT MAXIMUM MATERIAL CONDI-7. EXCESS OF DIMENSION 6 AT MAXIMUM MATERIAL CONDI-TION. THE DAMBAR CANNOT BE LOCATED ON THE LOWER RADIUS OF THE FOOT.

	MILLIMETERS			INCHES			
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α			1.10			0.043	
A1	0.00		0.10	0.000		0.004	
A2	0.70	0.90	1.00	0.027	0.035	0.039	
b	0.15	0.20	0.25	0.006	0.008	0.010	
С	0.08	0.15	0.22	0.003	0.006	0.009	
D	1.80	2.00	2.20	0.070	0.078	0.086	
Е	2.00	2.10	2.20	0.078	0.082	0.086	
E1	1.15	1.25	1.35	0.045	0.049	0.053	
е	0.65 BSC			0.026 BSC			
L	0.26	0.36	0.46	0.010	0.014	0.018	
L2	0.15 BSC			0.006 BSC			
aaa	0.15			0.006			
bbb	0.30			0.012			
CCC	0.10			0.004			
ddd	0.10			0.004			

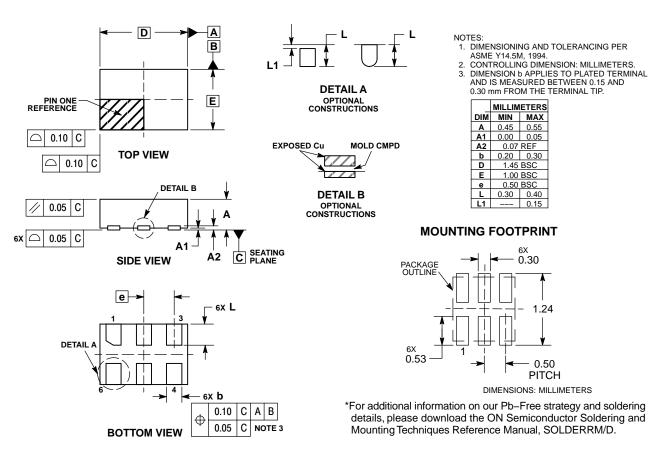
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